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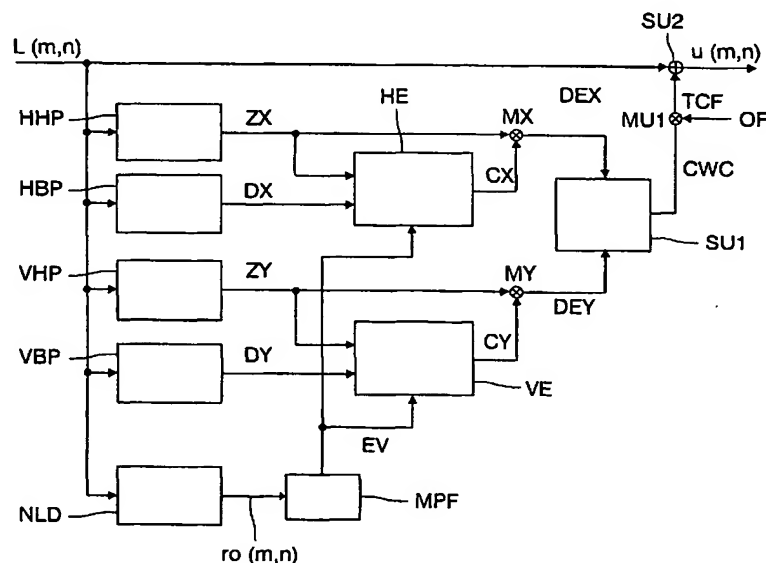
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(54) Title: **SHARPNESS ENHANCEMENT**



(57) Abstract: A two-dimensional enhancement function (HEF; VEF) determines a peaking factor (CX; CY) for an input signal ($L(m,n)$) based on the output signals of both a first edge detector (HHP; VHP) and a second edge detector (HBP; VBP) which both operate in the same first spatial direction. In this manner, all different kind of borders which may occur in the input signal ($L(m,n)$) in the first spatial direction are distinguished. The two-dimensional enhancement function (HEF; VEF) allocates values which determine the amount of peaking to the different combinations of the output signals (ZX, DX; ZY, DY). It is possible to select the values allocated by the two-dimensional enhancement function (HEF; VEF) different for different kind of borders to obtain the desired amount of peaking fitting each kind of border best.